

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Rishi Bhooshan, et al.

Art Unit: 2825

Serial No.: 10/710,693

Examiner: Phallaka Kik

Filed: 07/29/2004

Docket: TI-37087

For: ELECTRO-MIGRATION (EM) AND VOLTAGE (IR) DROP ANALYSIS OF
INTEGRATED CIRCUIT (IC) DESIGNS

Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

AMENDMENT UNDER C.F.R. § 1.111

In response to the Official Action in this case mailed July 3, 2006, please enter the following: